## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination TANGPUZ ET AL. | Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,316,205	05-1994	Melton, Cynthia	228/180.21
	В	US-6,316,822	11-2001	Venkateshwaran et al.	257/666
	Ç	US-6,457,233	10-2002	Shimizu, Kozo	29/840
	D	US-6,507,120	01-2003	Lo et al.	257/778
	Е	US-6,510,976	01-2003	Hwee et al.	228/180.22
	F	US-2002/0182843	12-2002	Pu, Han-Ping	438/615
	G	US-2003/0089923	05-2003	Oida et al.	257/200
	Н	US-2003/0143406	07-2003	Siegel et al.	428/447
	ı	US-2004/0169261	09-2004	litani et al.	257/676
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р					
	Q					
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	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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